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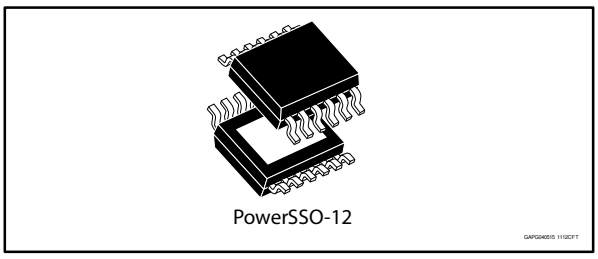
VND7140AJ12

Double channel high-side driver with CurrentSense analog feedback for automotive applications

Datasheet - production data



Features

Max transient supply voltage	V_{CC}	40 V
Operating voltage range	V_{CC}	4 V to 28 V
Minimum cranking supply voltage (V_{CC} decreasing)	$V_{USD\_Cranking}$	2.85 V
Typ. on-state resistance (per Ch)	R_{ON}	140 mΩ
Current limitation (typ)	I_{LIMH}	12 A
Standby current (max)	I_{STBY}	0.5 µA

- Automotive qualified
- Extreme low voltage operation for deep cold cranking applications (compliant with LV124, revision 2013)
- General
  - Double channel smart high-side driver with CurrentSense analog feedback
  - Very low standby current
  - Compatible with 3 V and 5 V CMOS outputs
- CurrentSense diagnostic functions
  - Multiplexed analog feedback of: load current with high precision proportional current mirror
  - Overload and short to ground (power limitation) indication
  - Thermal shutdown indication
  - Off-state open-load detection
  - Output short to V_{CC} detection
  - Sense enable/ disable
- Protections
  - Undervoltage shutdown
  - Overvoltage clamp
  - Load current limitation
  - Self limiting of fast thermal transients
  - Loss of ground and loss of V_{CC}
  - Reverse battery with external components
  - Electrostatic discharge protection

Applications

- All types of automotive resistive, inductive and capacitive loads
- Specially intended for automotive signal lamps (up to R10W or LED Rear Combinations)

Description

The device is a double channel high-side driver manufactured using ST proprietary VIPower® technology and housed in PowerSSO-12 package. The device is designed to drive 12 V automotive grounded loads through a 3 V and 5 V CMOS compatible interface, providing protection and diagnostics.

The device integrates advanced protective functions such as load current limitation, overload active management by power limitation and overtemperature shutdown.

A current sense delivers high precision proportional load current sense in addition to the detection of overload and short circuit to ground, short to V_{CC} and off-state open-load.

A sense enable pin allows off-state diagnosis to be disabled during the module low-power mode as well as external sense resistor sharing among similar devices.

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1 Block diagram and pin description

Figure 1: Block diagram

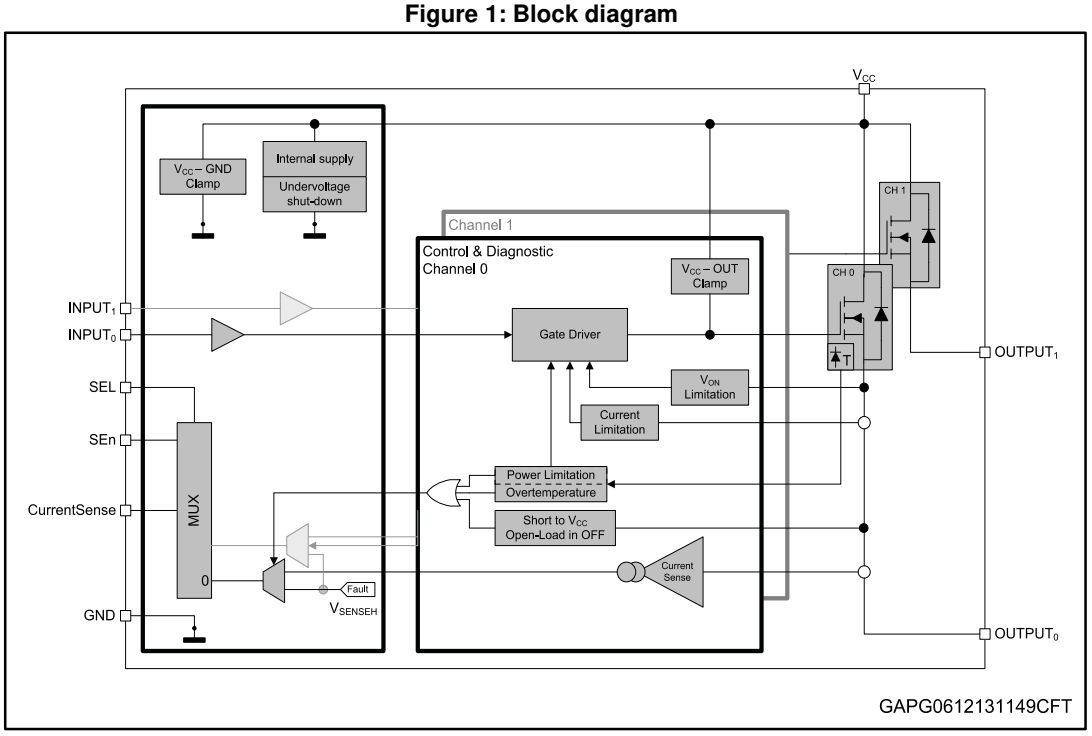


Table 1: Pin functions

Name	Function
V_{CC}	Battery connection.
$OUTPUT_{0,1}$	Power output.
GND	Ground connection. Must be reverse battery protected by an external diode/resistor network.
$INPUT_{0,1}$	Voltage controlled input pins with hysteresis, compatible with 3 V and 5 V CMOS outputs. They control output switch state.
CurrentSense	Multiplexed analog sense output pin; it delivers a current proportional to the load current.
SEn	Active high compatible with 3 V and 5 V CMOS outputs pin; it enables the CurrentSense diagnostic pin.
SEL	Active high compatible with 3 V and 5 V CMOS outputs pin; it addresses the CurrentSense multiplexer.

Figure 2: Configuration diagram (top view)

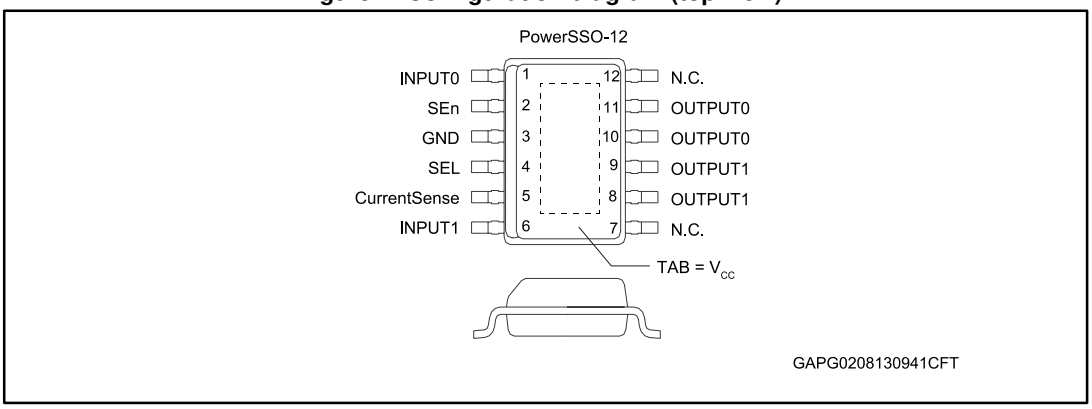


Table 2: Suggested connections for unused and not connected pins

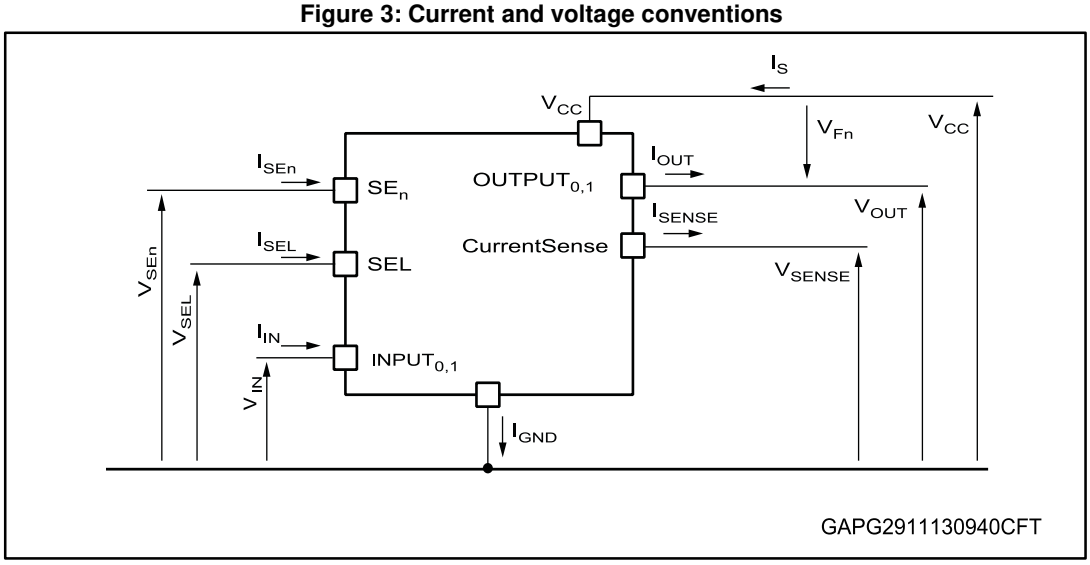
Connection/pin	CurrentSense	N.C.	Output	Input	SEn, SEL
Floating	Not allowed	X (1)	X	X	X
To ground	Through 1 kΩ resistor	X	Not allowed	Through 15 kΩ resistor	Through 15 kΩ resistor

Notes:

(1)X: do not care.

2 Electrical specification

Figure 3: Current and voltage conventions



$V_{Fn} = V_{OUTn} - V_{CC}$ during reverse battery condition.

2.1 Absolute maximum ratings

Stressing the device above the rating listed in *Table 3: "Absolute maximum ratings"* may cause permanent damage to the device. These are stress ratings only and operation of the device at these or any other conditions above those indicated in the operating sections of this specification is not implied. Exposure to the conditions in table below for extended periods may affect device reliability.

Table 3: Absolute maximum ratings

Symbol	Parameter	Value	Unit
V_{CC}	DC supply voltage	38	V
$-V_{CC}$	Reverse DC supply voltage	0.3	V
V_{CCPK}	Maximum transient supply voltage (ISO 16750-2:2010 Test B clamped to 40 V; R_L = 4 Ω)	40	V
V_{CCJS}	Maximum jump start voltage for single pulse short circuit protection	28	V
$-I_{GND}$	DC reverse ground pin current	200	mA
I_{OUT}	$OUTPUT_{0,1}$ DC output current	Internally limited	A
$-I_{OUT}$	Reverse DC output current	4	
I_{IN}	$INPUT_{0,1}$ DC input current	-1 to 10	mA
I_{SEn}	SEn DC input current		
I_{SEL}	SEL DC input current		
I_{SENSE}	CurrentSense pin DC output current (V_{GND} = V_{CC} and V_{SENSE} < 0 V)	10	mA
	CurrentSense pin DC output current in reverse (V_{CC} < 0V)	-20	

Symbol	Parameter	Value	Unit
E_{MAX}	Maximum switching energy (single pulse) (T_{DEMAG} = 0.4 ms; T_{jstart} = 150 °C)	10	mJ
V_{ESD}	Electrostatic discharge (JEDEC 22A-114F) • $INPUT_{0,1}$ • CurrentSense • SEn, SEL • $OUTPUT_{0,1}$ • V_{CC}	 4000 2000 4000 4000 4000	 V V V V V
V_{ESD}	Charge device model (CDM-AEC-Q100-011)	750	V
T_j	Junction operating temperature	-40 to 150	°C
T_{stg}	Storage temperature	-55 to 150	

2.2 Thermal data

Table 4: Thermal data

Symbol	Parameter	Typ. value	Unit
$R_{thj\text{-}board}$	Thermal resistance junction-board (JEDEC JESD 51-5 / 51-8) (1)(2)	7.7	°C/W
$R_{thj\text{-}amb}$	Thermal resistance junction-ambient (JEDEC JESD 51-5)(1)(3)	61	
$R_{thj\text{-}amb}$	Thermal resistance junction-ambient (JEDEC JESD 51-7)(1)(2)	26.5	

Notes:

(1)One channel ON.

(2)Device mounted on four-layers 2s2p PCB.

(3)Device mounted on two-layers 2s0p PCB with 2 cm^2 heatsink copper trace.

2.3 Main electrical characteristics

7 V < V_{CC} < 28 V; -40 °C < T_j < 150 °C, unless otherwise specified.

All typical values refer to V_{CC} = 13 V; T_j = 25°C, unless otherwise specified.

Table 5: Electrical characteristics during cranking

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$V_{USD\_Cranking}$	Minimum cranking supply voltage (V_{CC} decreasing)				2.85	V
R_{ON}	On-state resistance (1)	I_{OUT} = 0.2 A; V_{CC} = 2.85 V; V_{CC} decreasing			1400	mΩ
T_{TSD}(2)	Shutdown temperature (V_{CC} decreasing)	V_{CC} = 2.85 V	140			°C

Notes:

(1)For each channel.

(2)Parameter guaranteed by design and characterization; not subject to production test.

Table 6: Power section

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
V_{CC}	Operating supply voltage		4	13	28	V
V_{USD}	Undervoltage shutdown				2.85	
$V_{USDReset}$	Undervoltage shutdown reset				5	
$V_{USDhyst}$	Undervoltage shutdown hysteresis			0.3		
R_{ON}	On-state resistance (1)	I_{OUT} = 1 A; T_j = 25 °C		140		mΩ
		I_{OUT} = 1 A; T_j = 150 °C			280	
		I_{OUT} = 1 A; V_{CC} = 4 V; T_j = 25 °C			210	
V_{clamp}	Clamp voltage	I_S = 20 mA; T_j = -40 °C	38			V
		I_S = 20 mA; 25°C < T_j < 150°C	41	46	52	
I_{STBY}	Supply current in standby at V_{CC} = 13 V (2)	V_{CC} = 13 V; V_{IN} = V_{OUT} = V_{SEn} = 0 V; V_{SEL} = 0 V; T_j = 25 °C			0.5	µA
		V_{CC} = 13 V; V_{IN} = V_{OUT} = V_{SEn} = 0 V; V_{SEL} = 0 V; T_j = 85 °C (3)			0.5	µA
		V_{CC} = 13 V; V_{IN} = V_{OUT} = V_{SEn} = 0 V; V_{SEL} = 0 V; T_j = 125 °C			3	µA
t_{D_STBY}	Standby mode blanking time	V_{CC} = 13 V; V_{IN} = V_{OUT} = V_{SEL} = 0 V; V_{SEn} = 5 V to 0 V	60	300	550	µA
$I_{S(ON)}$	Supply current	V_{CC} = 13 V; V_{SEn} = V_{SEL} = 0 V; V_{IN0} = 5 V; V_{IN1} = 5 V; I_{OUT0} = 0 A; I_{OUT1} = 0 A		5	8	mA
$I_{GND(ON)}$	Control stage current consumption in ON state. All channels active.	V_{CC} = 13 V; V_{SEn} = 5 V; V_{SEL} = 0 V; V_{IN0} = 5 V; V_{IN1} = 5 V; I_{OUT0} = 1 A; I_{OUT1} = 1 A			12	mA
$I_{L(off)}$	Off-state output current at V_{CC} = 13 V (1)	V_{IN} = V_{OUT} = 0 V; V_{CC} = 13 V; T_j = 25 °C	0	0.01	0.5	µA
		V_{IN} = V_{OUT} = 0 V; V_{CC} = 13 V; T_j = 125 °C	0		3	
V_F	Output - V_{CC} diode voltage (1)	I_{OUT} = -1 A; T_j = 150 °C			0.7	V

Notes:

(1)For each channel.

(2)PowerMOS leakage included.

(3)Parameter specified by design; not subject to production test.

Table 7: Switching

V_{CC} = 13 V; -40°C < T_j < 150°C, unless otherwise specified						
Symbol	**Parameter**	**Test conditions**	**Min.**	**Typ.**	**Max.**	**Unit**
$t_{d(on)}$ (1)	Turn-on delay time at T_j = 25°C	R_L = 13 Ω	10	70	120	µs
$t_{d(off)}$ (1)	Turn-off delay time at T_j = 25°C		10	40	100	
$(dV_{OUT}/dt)_{on}$ (1)	Turn-on voltage slope at T_j = 25°C	R_L = 13 Ω	0.1	0.27	0.7	V/µs
$(dV_{OUT}/dt)_{off}$ (1)	Turn-off voltage slope at T_j = 25°C		0.1	0.35	0.7	

V_{CC} = 13 V; -40°C < T_j < 150°C, unless otherwise specified						
Symbol	**Parameter**	**Test conditions**	**Min.**	**Typ.**	**Max.**	**Unit**
W_{ON}	Switching energy losses at turn-on (t_{won})	R_L = 13 Ω	—	0.15	0.18 (2)	mJ
W_{OFF}	Switching energy losses at turn-off (t_{woff})	R_L = 13 Ω	—	0.1	0.18(2)	mJ
t_{SKEW}(1)	Differential pulse skew (t_{PHL} - t_{PLH})	R_L = 13 Ω	-100	-50	0	µs

Notes:

(1)See *Figure 6: "Switching times and Pulse skew"*

(2)Parameter guaranteed by design and characterization; not subject to production test.

Table 8: Logic inputs

7 V < V_{CC} < 28 V; -40°C < T_j < 150°C						
Symbol	**Parameter**	**Test conditions**	**Min.**	**Typ.**	**Max.**	**Unit**
$INPUT_{0,1}$ characteristics						
V_{IL}	Input low level voltage				0.9	V
I_{IL}	Low level input current	V_{IN} = 0.9 V	1			µA
V_{IH}	Input high level voltage		2.1			V
I_{IH}	High level input current	V_{IN} = 2.1 V			10	µA
$V_{I(hyst)}$	Input hysteresis voltage		0.2			V
V_{ICL}	Input clamp voltage	I_{IN} = 1 mA	5.3		7.2	V
		I_{IN} = -1 mA		-0.7		
SEL characteristics (7 V < V_{CC} < 18 V)						
V_{SELL}	Input low level voltage				0.9	V
I_{SELL}	Low level input current	V_{IN} = 0.9 V	1			µA
V_{SELH}	Input high level voltage		2.1			V
I_{SELH}	High level input current	V_{IN} = 2.1 V			10	µA
$V_{SEL(hyst)}$	Input hysteresis voltage		0.2			V
V_{SELCL}	Input clamp voltage	I_{IN} = 1 mA	5.3		7.2	V
		I_{IN} = -1 mA		-0.7		
SEn characteristics (7 V < V_{CC} < 18 V)						
V_{SEnL}	Input low level voltage				0.9	V
I_{SEnL}	Low level input current	V_{IN} = 0.9 V	1			µA
V_{SEnH}	Input high level voltage		2.1			V
I_{SEnH}	High level input current	V_{IN} = 2.1 V			10	µA
$V_{SEn(hyst)}$	Input hysteresis voltage		0.2			V
V_{SEnCL}	Input clamp voltage	I_{IN} = 1 mA	5.3		7.2	V
		I_{IN} = -1 mA		-0.7		

Table 9: Protections

7 V < V_{CC} < 18 V; -40°C < T_j < 150°C						
Symbol	**Parameter**	**Test conditions**	**Min.**	**Typ.**	**Max.**	**Unit**
I_{LIMH}	DC short circuit current	V_{CC} = 13 V	8	12	16	A
		4 V < V_{CC} < 18 V (1)			16	
I_{LIML}	Short circuit current during thermal cycling	V_{CC} = 13 V; T_R < T_j < T_{TSD}		4		
T_{TSD}	Shutdown temperature		150	175	200	°C
T_R	Reset temperature(1)		T_{RS} + 1	T_{RS} + 7		
T_{RS}	Thermal reset of fault diagnostic indication	V_{SEn} = 5 V	135			
T_{HYST}	Thermal hysteresis (T_{TSD} - T_R)(1)			7		
ΔT_{J_SD}	Dynamic temperature	T_j = -40 °C; V_{CC} = 13 V		60		K
V_{DEMAG}	Turn-off output voltage clamp	I_{OUT} = 1 A; L = 6 mH; T_j = -40 °C	V_{CC} - 38			V
		I_{OUT} = 1 A; L = 6 mH; T_j = 25 °C to +150 °C	V_{CC} - 41	V_{CC} - 46	V_{CC} - 52	
V_{ON}	Output voltage drop limitation	I_{OUT} = 0.07 A		20		mV

Notes:

(1)Parameter guaranteed by design and characterization; not subject to production test.

Table 10: CurrentSense

7 V < V_{CC} < 18 V; -40°C < T_j < 150°C						
Symbol	**Parameter**	**Test conditions**	**Min.**	**Typ.**	**Max.**	**Unit**
V_{SENSE_CL}	CurrentSense clamp voltage	V_{SEn} = 0 V; I_{SENSE} = 1 mA	-17		-12	V
		V_{SEn} = 0 V; I_{SENSE} = -1 mA		7		V
CurrentSense characteristics						
K_{OL}	I_{OUT}/I_{SENSE}	I_{OUT} = 0.01 A; V_{SENSE} = 0.5 V; V_{SEn} = 5 V	295			
dK_{cal}/K_{cal}(1)(2)	Current sense ratio drift at calibration point	I_{OUT} = 0.01 A to 0.025 A; I_{cal} = 17.5 mA; V_{SENSE} = 0.5 V; V_{SEn} = 5 V	-30		30	%
K_{LED}	I_{OUT}/I_{SENSE}	I_{OUT} = 0.025 A; V_{SENSE} = 0.5 V; V_{SEn} = 5 V	330	580	820	
dK_{LED}/K_{LED}(1)(2)	Current sense ratio drift	I_{OUT} = 0.025 A; V_{SENSE} = 0.5 V; V_{SEn} = 5 V	-25		25	%
K_0	I_{OUT}/I_{SENSE}	I_{OUT} = 0.07 A; V_{SENSE} = 0.5 V; V_{SEn} = 5 V	375	550	720	
dK_0/K_0(1)(2)	Current sense ratio drift	I_{OUT} = 0.07 A; V_{SENSE} = 0.5 V; V_{SEn} = 5 V	-20		20	%
K_1	I_{OUT}/I_{SENSE}	I_{OUT} = 0.15 A; V_{SENSE} = 4 V; V_{SEn} = 5 V	360	500	670	

7 V < V_{CC} < 18 V; -40°C < T_j < 150°C						
Symbol	**Parameter**	**Test conditions**	**Min.**	**Typ.**	**Max.**	**Unit**
dK_1/K_1 (1)(2)	Current sense ratio drift	I_{OUT} = 0.15 A; V_{SENSE} = 4 V; V_{SEn} = 5 V	-15		15	%
K_2	I_{OUT}/I_{SENSE}	I_{OUT} = 0.7 A; V_{SENSE} = 4 V; V_{SEn} = 5 V	380	475	570	
dK_2/K_2 (1)(2)	Current sense ratio drift	I_{OUT} = 0.7 A; V_{SENSE} = 4 V; V_{SEn} = 5 V	-10		10	%
K_3	I_{OUT}/I_{SENSE}	I_{OUT} = 2 A; V_{SENSE} = 4 V; V_{SEn} = 5 V	430	470	520	
dK_3/K_3 (1)(2)	Current sense ratio drift	I_{OUT} = 2 A; V_{SENSE} = 4 V; V_{SEn} = 5 V	-5		5	%
I_{SENSE0}	CurrentSense leakage current	CurrentSense disabled: V_{SEn} = 0 V	0		0.5	µA
		CurrentSense disabled: -1 V < V_{SENSE} < 5 V (1)	-0.5		0.5	µA
		CurrentSense enabled: V_{SEn} = 5 V; All channel ON; I_{OUTX} = 0 A; Ch_X diagnostic selected; • E.g. Ch_0: V_{IN0} = 5 V; V_{IN1} = 5 V; V_{SEL} = 0 V; I_{OUT0} = 0 A; I_{OUT1} = 1 A	0		2	µA
		CurrentSense enabled: V_{SEn} = 5 V; Ch_X channel OFF; Ch_X diagnostic selected; • E.g. Ch_0: V_{IN0} = 0 V; V_{IN1} = 5 V; V_{SEL} = 0 V; I_{OUT1} = 1 A	0		2	µA
V_{OUT_MSD} (1)	Output Voltage for CurrentSense shutdown	V_{SEn} = 5 V; R_{SENSE} = 2.7 kΩ • E.g. Ch_0: V_{IN0} = 5 V; V_{SEL} = 0 V; I_{OUT0} = 1 A		5		V
V_{SENSE_SAT}	CurrentSense saturation voltage	V_{CC} = 7 V; R_{SENSE} = 2.7 kΩ; V_{SEn} = 5 V; V_{IN0} = 5 V; V_{SEL} = 0 V; I_{OUT0} = 1 A; T_j = 150°C	5			V
I_{SENSE_SAT} (1)	CS saturation current	V_{CC} = 7 V; V_{SENSE} = 4 V; V_{IN0} = 5 V; V_{SEn} = 5 V; V_{SEL0} = 0 V; V_{SEL1} = 0 V; T_j = 150°C	4			mA

7 V < V_{CC} < 18 V; -40°C < T_j < 150°C						
Symbol	**Parameter**	**Test conditions**	**Min.**	**Typ.**	**Max.**	**Unit**
I_{OUT_SAT} (1)	Output saturation current	V_{CC} = 7 V; V_{SENSE} = 4 V; V_{IN0} = 5 V; V_{SEn} = 5 V; V_{SEL} = 0 V; T_j = 150°C	2.2			A
Off-state diagnostic						
V_{OL}	Off-state open-load voltage detection threshold	V_{SEn} = 5 V; Ch_X OFF; Ch_X diagnostic selected • E.g: Ch_0 V_{IN0} = 0 V; V_{SEL} = 0 V	2	3	4	V
$I_{L(off2)}$	Off-state output sink current	V_{IN} = 0 V; V_{OUT} = V_{OL}; T_j = -40 °C to 125 °C	-100		-15	µA
t_{DSTKON}	Off-state diagnostic delay time from falling edge of INPUT (see *Figure 8: "TDSTKON"*)	V_{SEn} = 5 V; Ch_X ON to OFF transition Ch_X diagnostic selected • E.g: Ch_0 V_{IN0} = 5 V to 0 V; V_{SEL} = 0 V; I_{OUT0} = 0 A; V_{OUT} = 4 V	100	350	700	µs
$t_{D\_OL\_V}$	Settling time for valid OFF-state open load diagnostic indication from rising edge of SEn	V_{IN0} = 0 V; V_{IN1} = 0 V; V_{SEL} = 0 V; V_{OUT0} = 4 V; V_{SEn} = 0 V to 5 V			60	µs
t_{D_VOL}	Off-state diagnostic delay time from rising edge of V_{OUT}	V_{SEn} = 5 V; Ch_X OFF Ch_X diagnostic selected • E.g: Ch_0 V_{IN0} = 0 V; V_{SEL} = 0 V; V_{OUT} = 0 V to 4 V		5	30	µs
Fault diagnostic feedback (see *Table 11: "Truth table"*)						
V_{SENSEH}	CurrentSense output voltage in fault condition	V_{CC} = 13 V; R_{SENSE} = 1 kΩ • E.g: Ch_0 in open load V_{IN0} = 0 V; V_{SEn} = 5 V; V_{SEL} = 0 V; I_{OUT0} = 0 A; V_{OUT} = 4 V	5		6.6	V
I_{SENSEH}	CurrentSense output current in fault condition	V_{CC} = 13 V; V_{SENSE} = 5 V	7	20	30	mA
CurrentSense timings (current sense mode - see *Figure 7: "CurrentSense timings"*) (3)						
$t_{DSENSE1H}$	Current sense settling time from rising edge of SEn	V_{IN} = 5 V; V_{SEn} = 0 V to 5 V; R_{SENSE} = 1 kΩ; R_L = 13 Ω			60	µs
$t_{DSENSE1L}$	Current sense disable delay time from falling edge of SEn	V_{IN} = 5 V; V_{SEn} = 5 V to 0 V; R_{SENSE} = 1 kΩ; R_L = 13 Ω		5	20	µs

7 V < V_{CC} < 18 V; -40°C < T_j < 150°C						
Symbol	**Parameter**	**Test conditions**	**Min.**	**Typ.**	**Max.**	**Unit**
$t_{DSENSE2H}$	Current sense settling time from rising edge of INPUT	V_{IN} = 0 V to 5 V; V_{SEn} = 5 V; R_{SENSE} = 1 kΩ; R_L = 13 Ω		100	250	µs
$\Delta t_{DSENSE2H}$	Current sense settling time from rising edge of I_{OUT} (dynamic response to a step change of I_{OUT})	V_{IN} = 5 V; V_{SEn} = 5 V; R_{SENSE} = 1 kΩ; I_{SENSE} = 90 % of $I_{SENSEMAX}$; R_L = 13 Ω			100	µs
$t_{DSENSE2L}$	Current sense turn-off delay time from falling edge of INPUT	V_{IN} = 5 V to 0 V; V_{SEn} = 5 V; R_{SENSE} = 1 kΩ; R_L = 13 Ω		50	250	µs
CurrentSense timings (Multiplexer transition times) *(3)*						
t_{D_XtoY}	CurrentSense transition delay from Ch_X to Ch_Y	V_{IN0} = 5 V; V_{IN1} = 5 V; V_{SEn} = 5 V; V_{SEL} = 0 V to 5 V; I_{OUT0} = 0 A; I_{OUT1} = 1 A; R_{SENSE} = 1 kΩ			20	µs
$t_{D\_CStoVSENSEH}$	CurrentSense transition delay from stable current sense on Ch_X to V_{SENSEH} on Ch_Y	V_{IN0} = 5 V; V_{IN1} = 0 V; V_{SEn} = 5 V; V_{SEL} = 0 V to 5 V; I_{OUT0} = 1 A; V_{OUT1} = 4 V; R_{SENSE} = 1 kΩ			60	µs

Notes:

(1)Parameter guaranteed by design and characterization; not subject to production test.

(2)All values refer to V_{CC} = 13 V; T_j = 25°C, unless otherwise specified.

(3)Transition delays are measured up to +/- 10% of final conditions.

Figure 4: IOUT/ISENSE versus IOUT

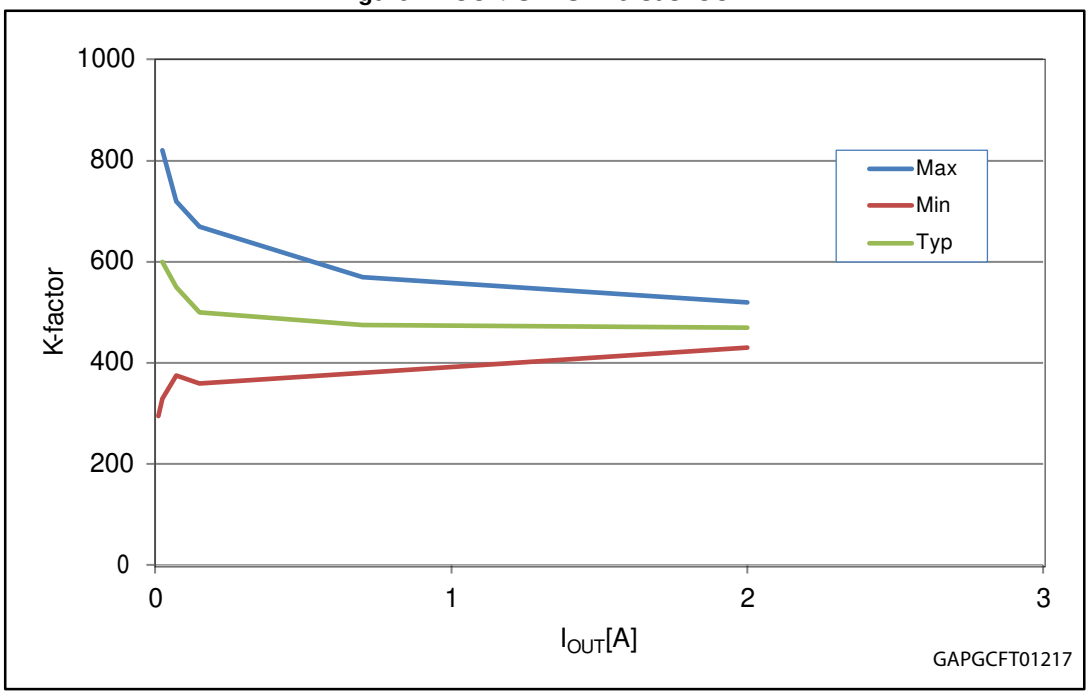


Figure 5: Current sense accuracy versus IOUT

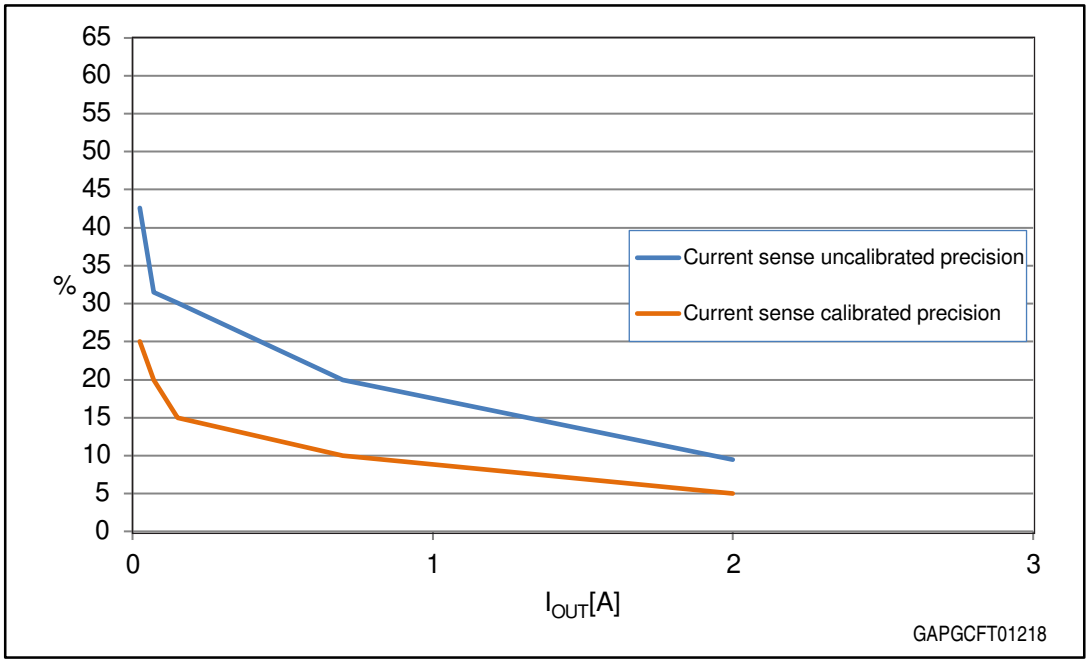


Figure 6: Switching times and Pulse skew

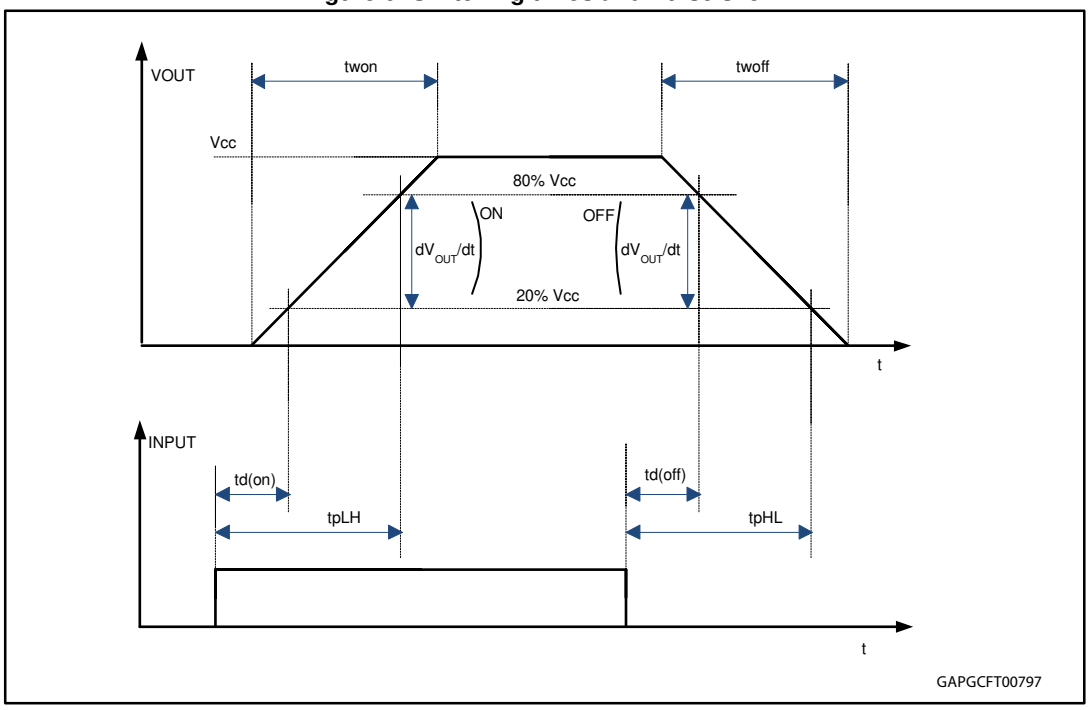


Figure 7: CurrentSense timings

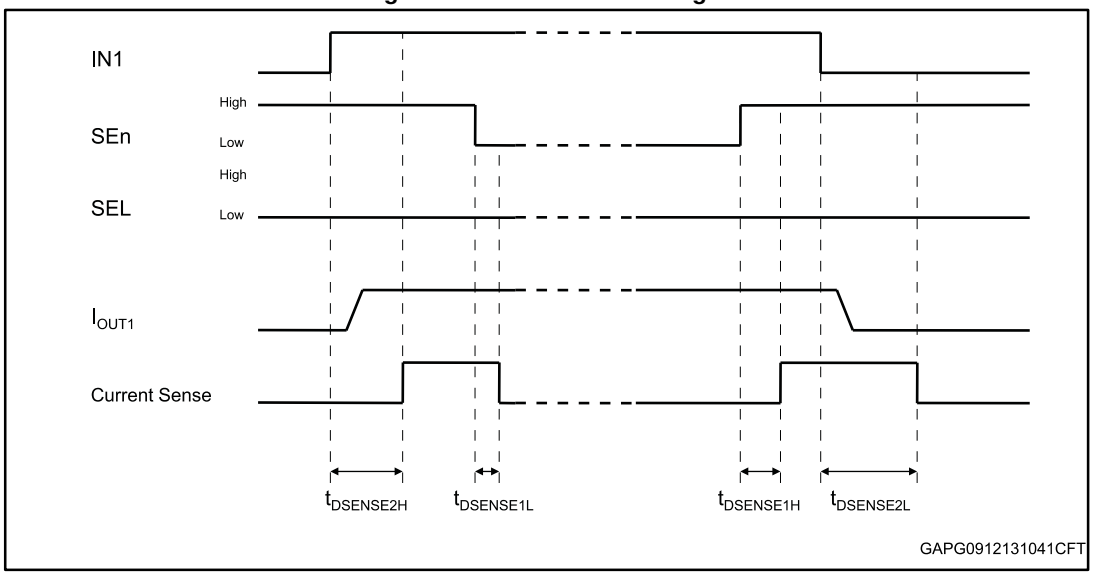


Figure 8: TDSTKON

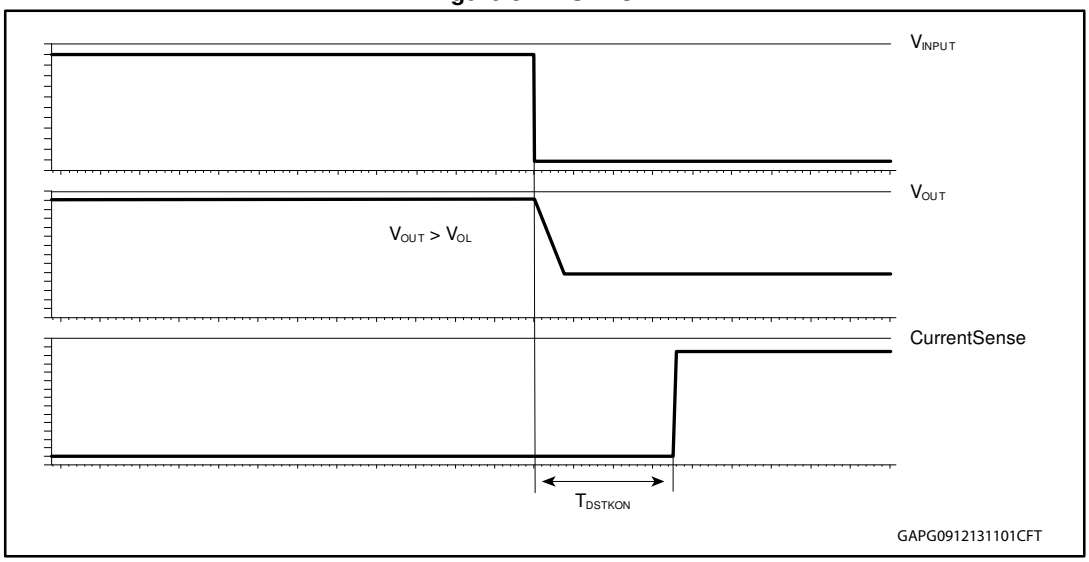


Table 11: Truth table

Mode	Conditions	IN_X	SEn	SEL	OUT_X	CurrentSense	Comments
Standby	All logic inputs low	L	L	L	L	Hi-Z	Low quiescent current consumption
Normal	Nominal load connected; T_j < 150°C	L	See (1)		L	See (1)	
		H			H	See (1)	Outputs configured for auto-restart
		H			H	See (1)	Outputs configured for latch off
Overload	Overload or short to GND causing: $T_j > T_{TSD}$ or $\Delta T_j > \Delta T_{j\_SD}$	L	See (1)		L	See (1)	
		H			H	See (1)	Output cycles with temperature hysteresis
		H			L	See (1)	Output latches off
Under-voltage	$V_{CC} < V_{USD}$ (falling)	X	X	X	L L	Hi-Z Hi-Z	Re-start when $V_{CC} > V_{USD} + V_{USDhyst}$ (rising)
Off-state diagnostics	Short to V_{CC}	L	See (1)		H	See (1)	
	Open-load	L			H	See (1)	External pull up
Negative output voltage	Inductive loads turn-off	L	See (1)		< 0 V	See (1)	

Notes:

(1)Refer to *Table 12: "CurrentSense multiplexer addressing"*

Table 12: CurrentSense multiplexer addressing

SEn	SEL	MUX channel	CurrentSense output			
			Normal mode	Overload	Off-state diag.	Negative output
L	X		Hi-Z			
H	L	Channel 0 diagnostic	I_{SENSE} = 1/K * I_{OUT0}	V_{SENSE} = V_{SENSEH}	V_{SENSE} = V_{SENSEH}	Hi-Z
H	H	Channel 1 diagnostic	I_{SENSE} = 1/K * I_{OUT1}	V_{SENSE} = V_{SENSEH}	V_{SENSE} = V_{SENSEH}	Hi-Z

2.4 Waveforms

Figure 9: Standby mode activation

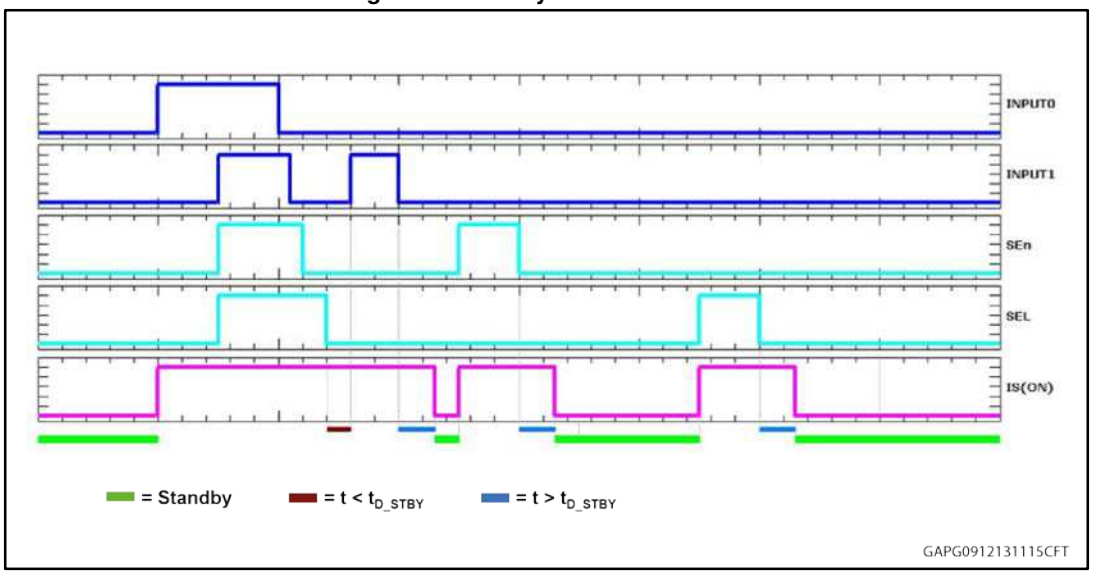
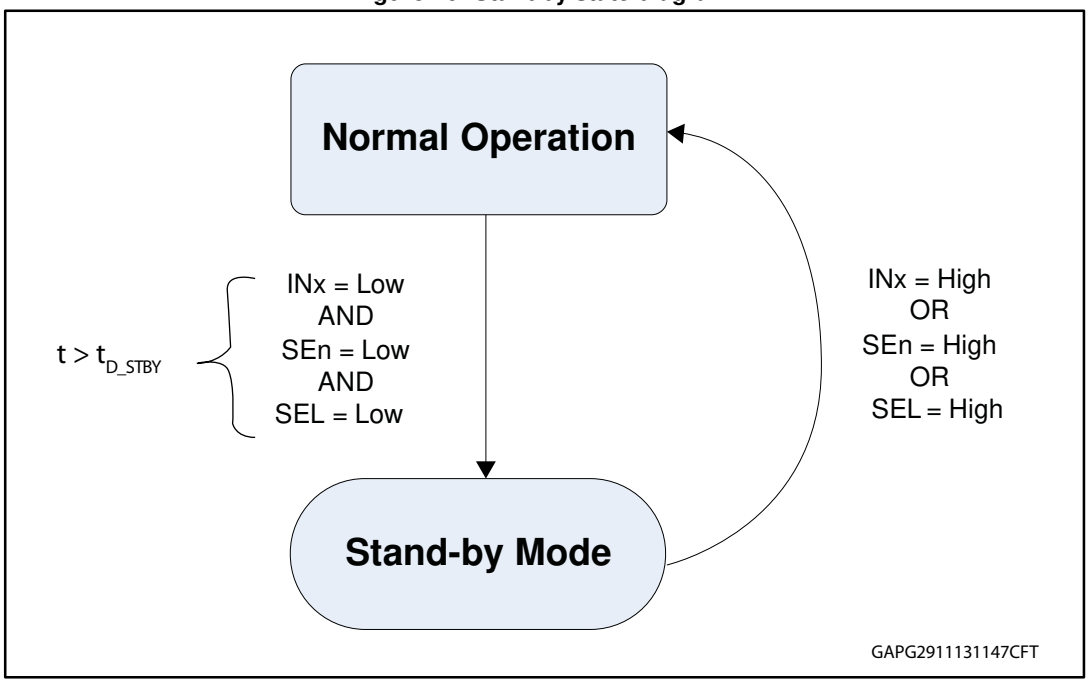


Figure 10: Standby state diagram



2.5 Electrical characteristics curves

Figure 11: OFF-state output current

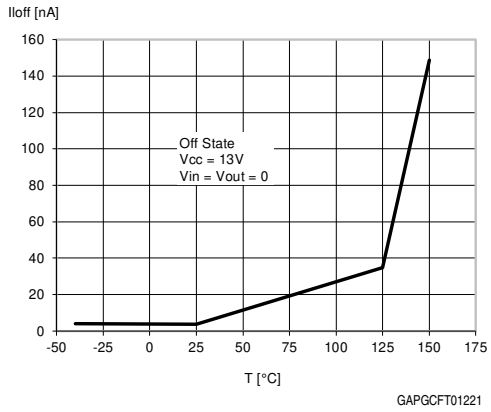


Figure 12: Standby current

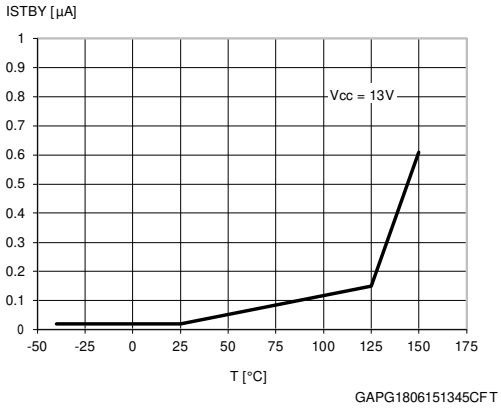


Figure 13: IGND(ON) vs. Tcase

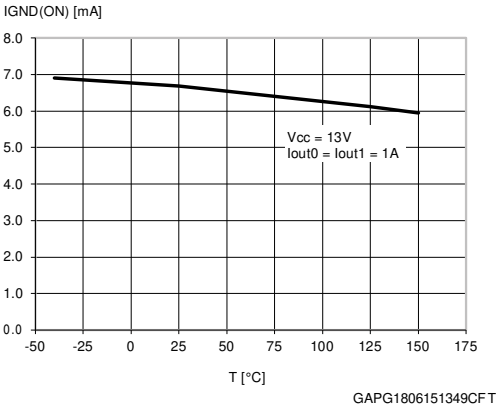


Figure 14: Logic Input high level voltage

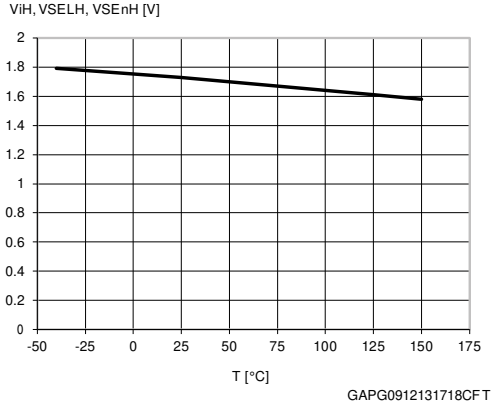


Figure 15: Logic Input low level voltage

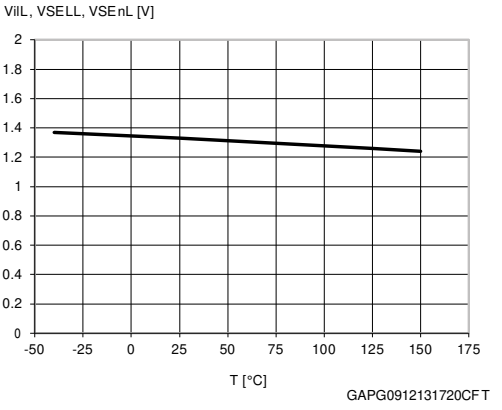


Figure 16: High level logic input current

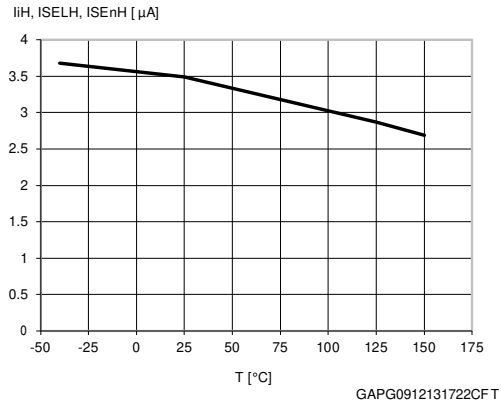


Figure 17: Low level logic input current

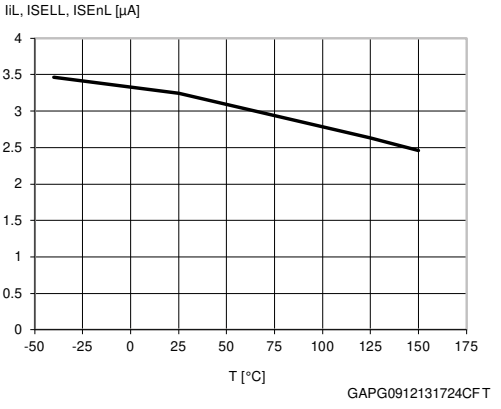


Figure 18: Logic Input hysteresis voltage

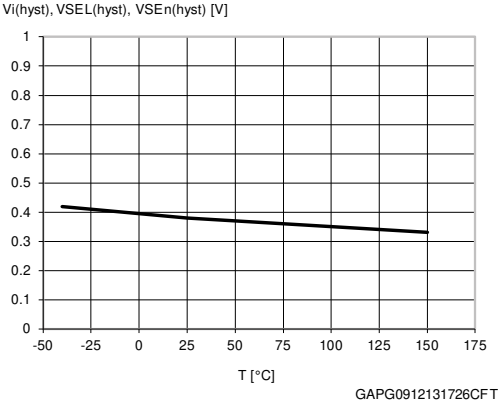


Figure 19: Undervoltage shutdown

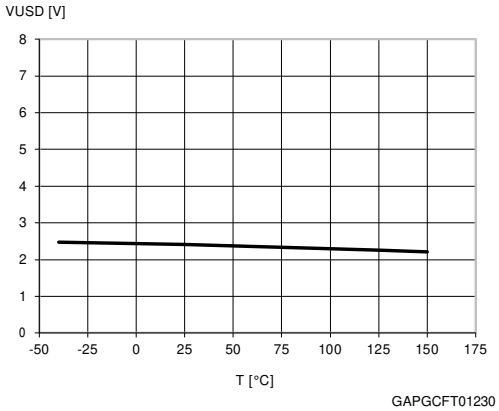


Figure 20: On-state resistance vs. Tcase

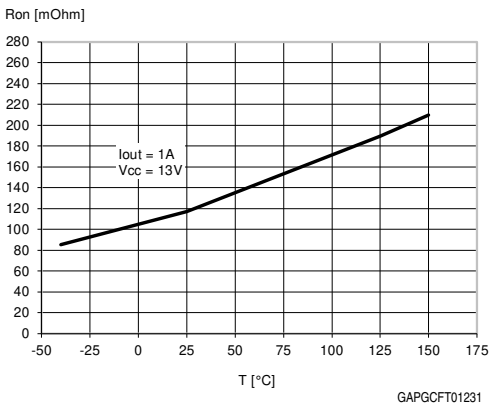


Figure 21: On-state resistance vs. Vcc

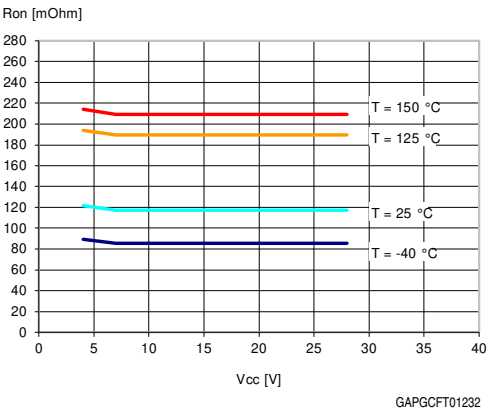


Figure 22: Turn-on voltage slope

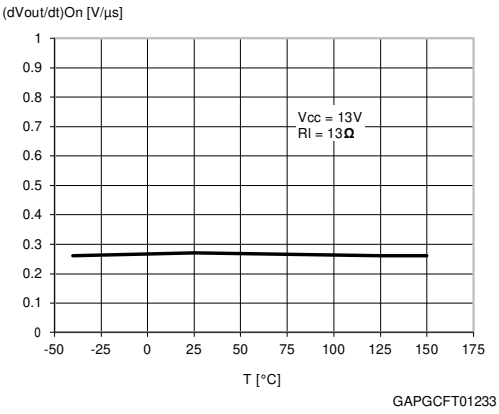


Figure 23: Turn-off voltage slope

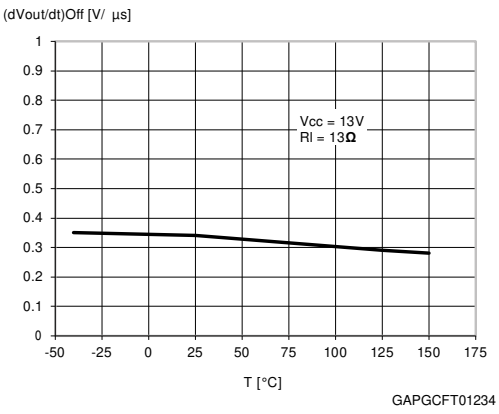


Figure 24: Won vs Tcase

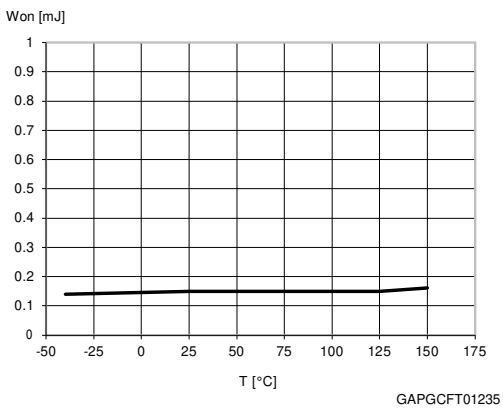


Figure 25: Woff vs Tcase

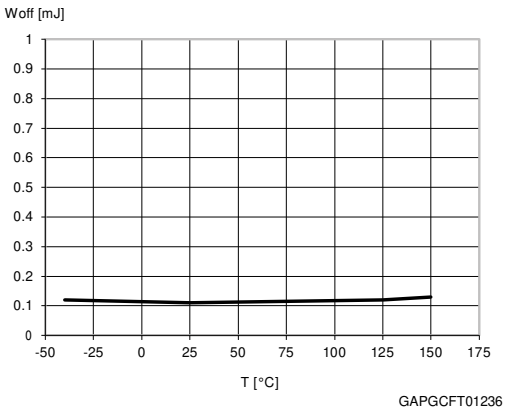


Figure 26: ILIMH vs. Tcase

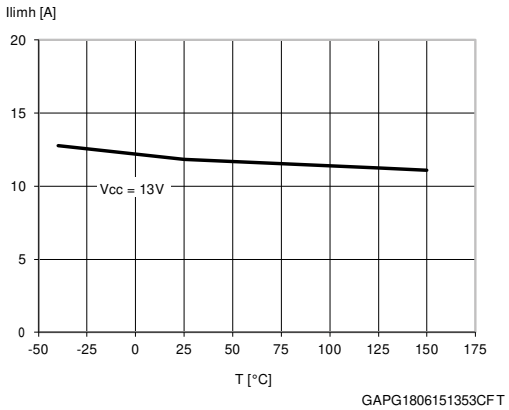


Figure 27: OFF-state open-load voltage detection threshold

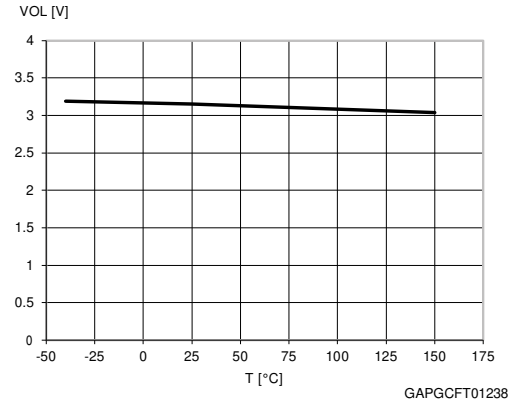


Figure 28: Vsense clamp vs Tcase

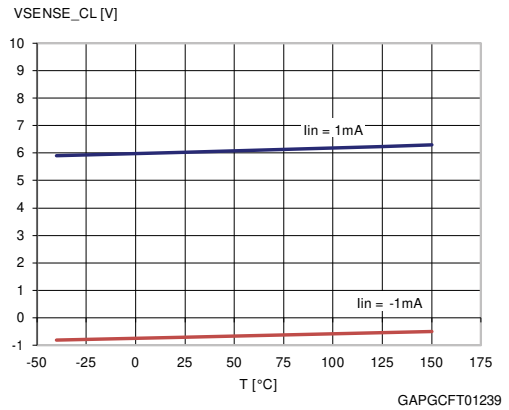
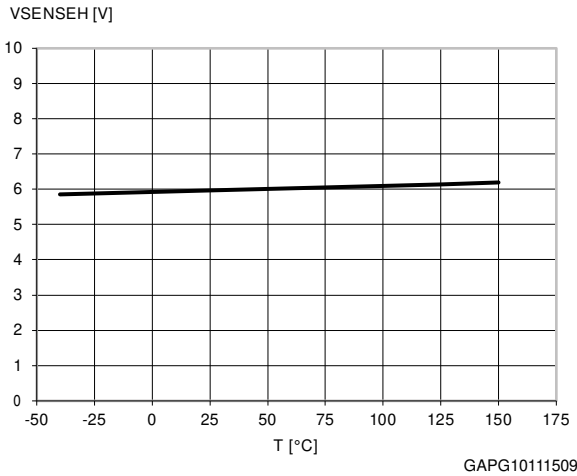


Figure 29: Vsenseh vs Tcase



3 Protections

3.1 Power limitation

The basic working principle of this protection consists of an indirect measurement of the junction temperature swing ΔT_j through the direct measurement of the spatial temperature gradient on the device surface in order to automatically shut off the output MOSFET as soon as ΔT_j exceeds the safety level of ΔT_{j_SD}. The output MOSFET switches on and cycles with a thermal hysteresis according to the maximum instantaneous power which can be handled. The protection prevents fast thermal transient effects and, consequently, reduces thermo-mechanical fatigue.

3.2 Thermal shutdown

In case the junction temperature of the device exceeds the maximum allowed threshold (typically 175°C), it automatically switches off and the diagnostic indication is triggered. The device switches on again as soon as its junction temperature drops to T_R.

3.3 Current limitation

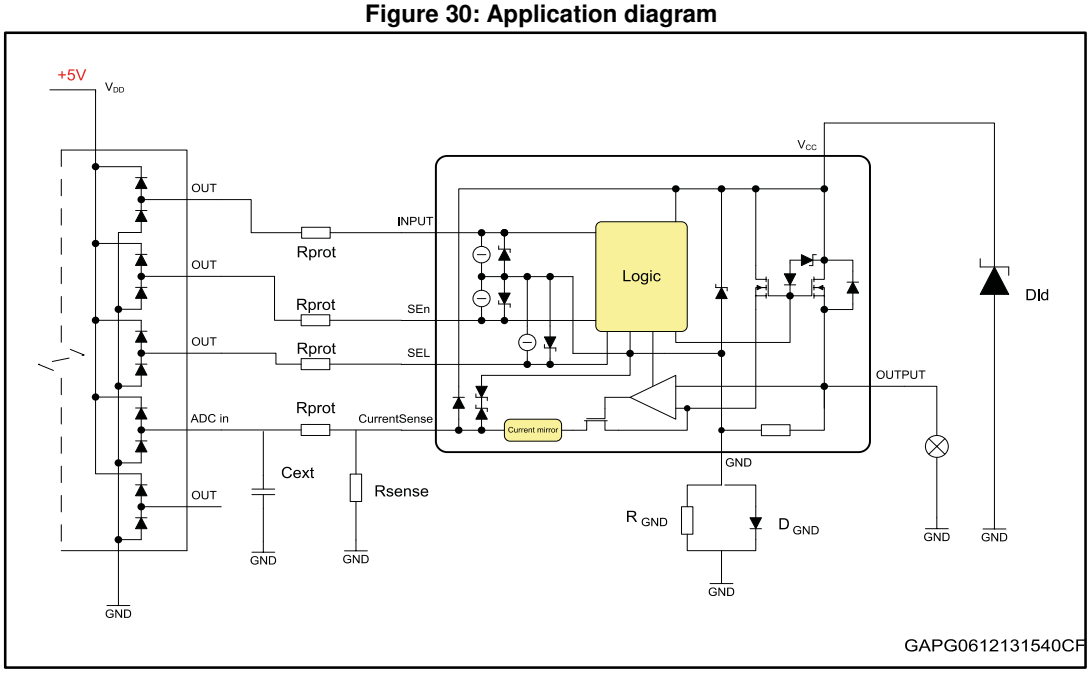
The device is equipped with an output current limiter in order to protect the silicon as well as the other components of the system (e.g. bonding wires, wiring harness, connectors, loads, etc.) from excessive current flow. Consequently, in case of short circuit, overload or during load power-up, the output current is clamped to a safety level, I_{LIMH}, by operating the output power MOSFET in the active region.

3.4 Negative voltage clamp

In case the device drives inductive load, the output voltage reaches a negative value during turn off. A negative voltage clamp structure limits the maximum negative voltage to a certain value, V_{DEMAG}, allowing the inductor energy to be dissipated without damaging the device.

4 Application information

Figure 30: Application diagram



4.1 GND protection network against reverse battery

Figure 31: Simplified internal structure - GND network protection with Schottly diode

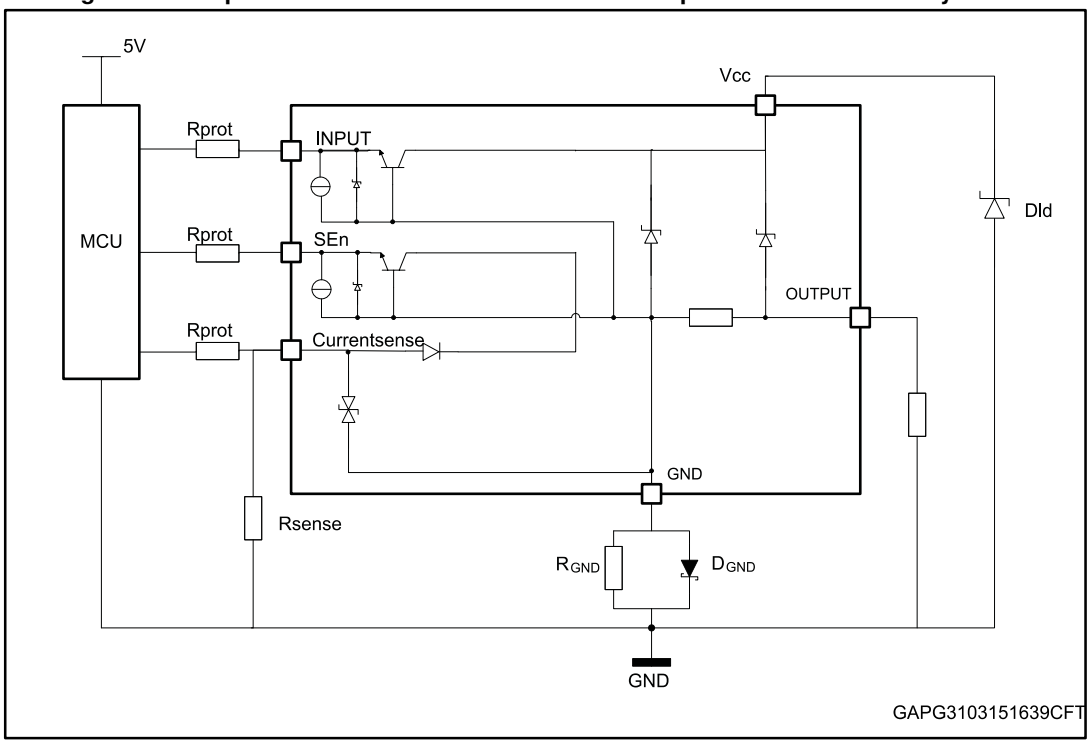
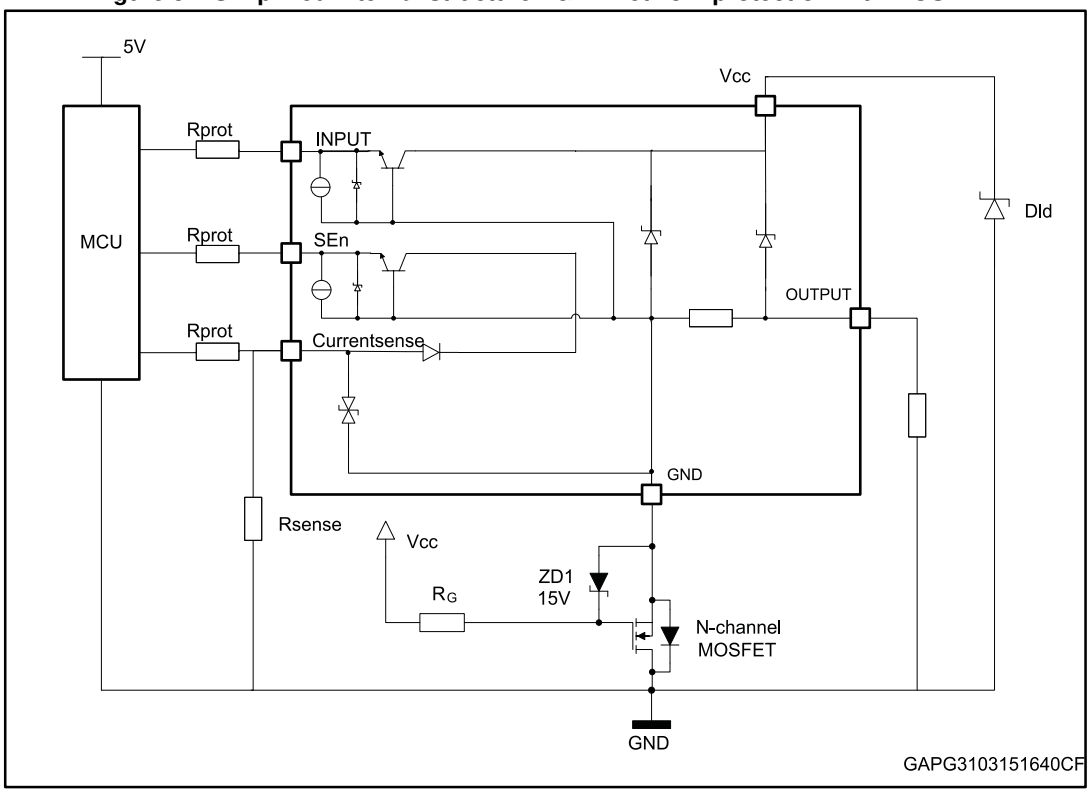


Figure 32: Simplified internal structure - GND network protection with MOSFET



4.1.1 Diode (DGND) in the ground line

A resistor (typ. R_{GND} = 4.7 kΩ) should be inserted in parallel to D_{GND} if the device drives an inductive load.

This small signal diode can be safely shared amongst several different HSDs. Also in this case, the presence of the ground network produces a shift (»600 mV) in the input threshold and in the status output values if the microprocessor ground is not common to the device ground. This shift does not vary if more than one HSD shares the same diode/resistor network.

To comply with LV124, E-11 "severe" start pulse, a Schottky diode (see *Figure 31: "Simplified internal structure - GND network protection with Schottly diode"*) or N-channel MOSFET (see *Figure 32: "Simplified internal structure - GND network protection with MOSFET"*) is recommended in order to ensure a lower ground network shift (≤ 350 mV).

4.2 Immunity against transient electrical disturbances

The immunity of the device against transient electrical emissions, conducted along the supply lines and injected into the V_{CC} pin, is tested in accordance with ISO7637-2:2011 (E) and ISO 16750-2:2010.

The related function performance status classification is shown in *Table 13: "ISO 7637-2 - electrical transient conduction along supply line"*.

Test pulses are applied directly to DUT (Device Under Test) both in ON and OFF-state and in accordance to ISO 7637-2:2011(E), chapter 4. The DUT is intended as the present device only, without components and accessed through V_{CC} and GND terminals.